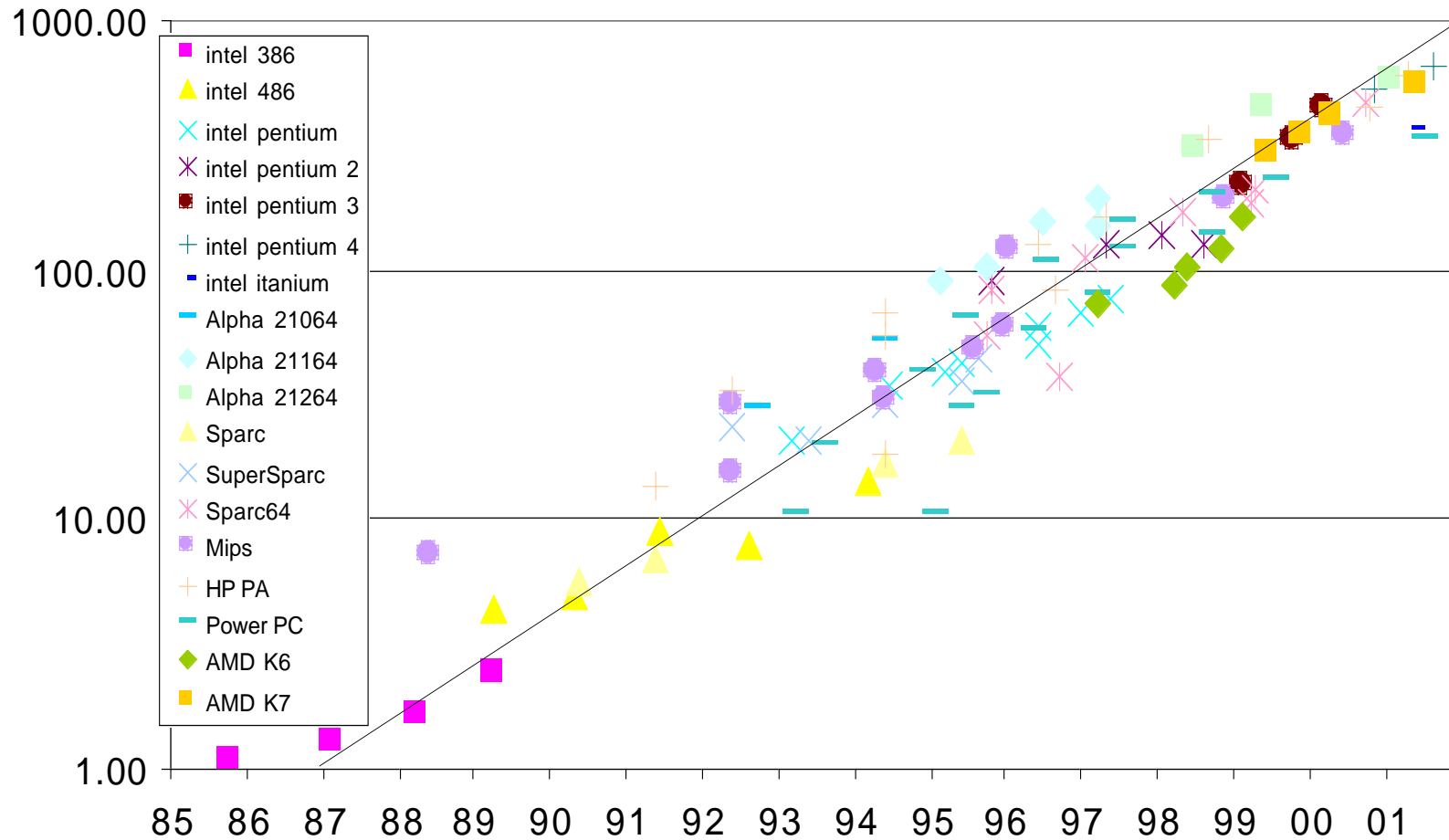

Lecture 2 continued

Wire Modeling

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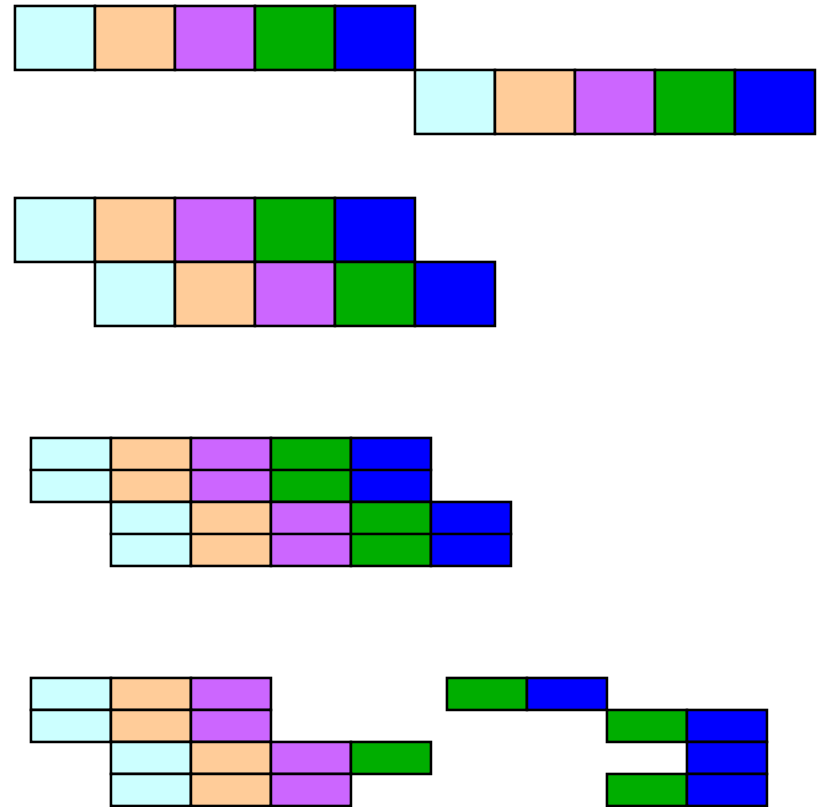
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Fruits of Scaling – SpecInt 2000



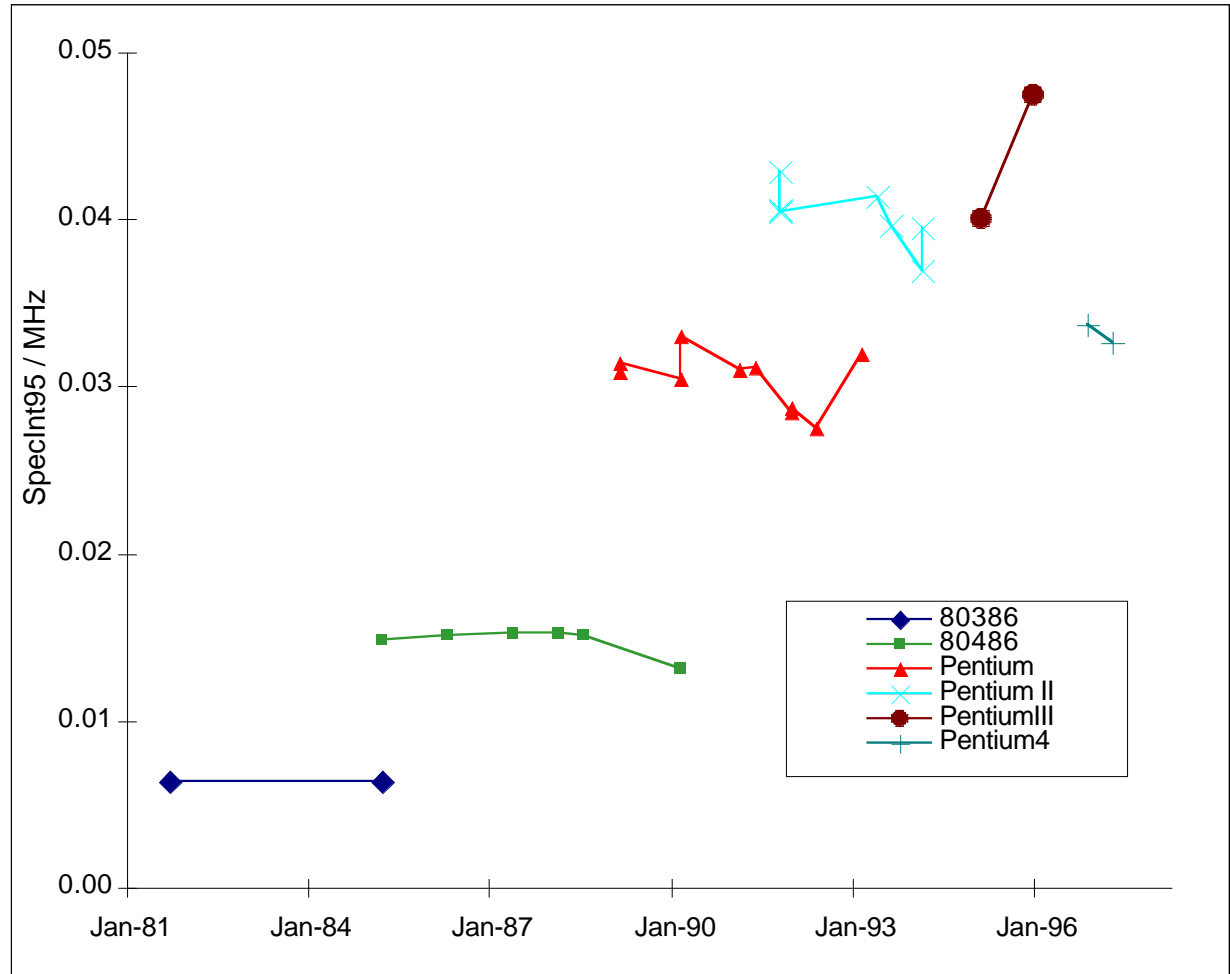
Computer Architect's Job

- Convert transistors to performance
- Use transistors to
 - Exploit parallelism
 - Or create it (speculate)
- Processor generations
 - Simple machine
 - Reuse hardware
 - Pipelined
 - Separate hardware for each stage
 - Super-scalar
 - Multiple port mems, function units
 - Out-of-order
 - Mega-ports, complex scheduling
 - Speculation
- Each design has more logic to accomplish same task (but faster)

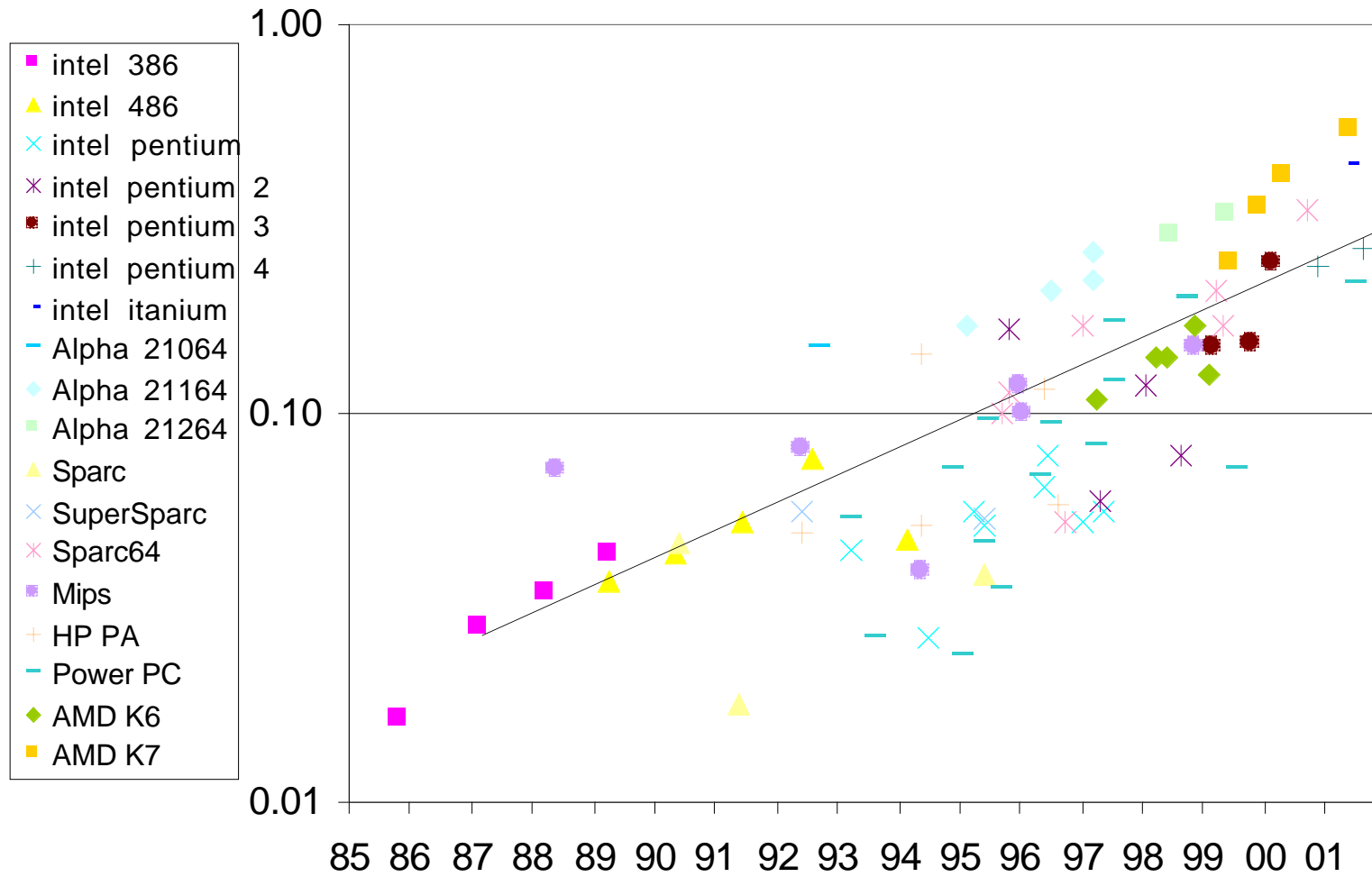


Architecture Scaling

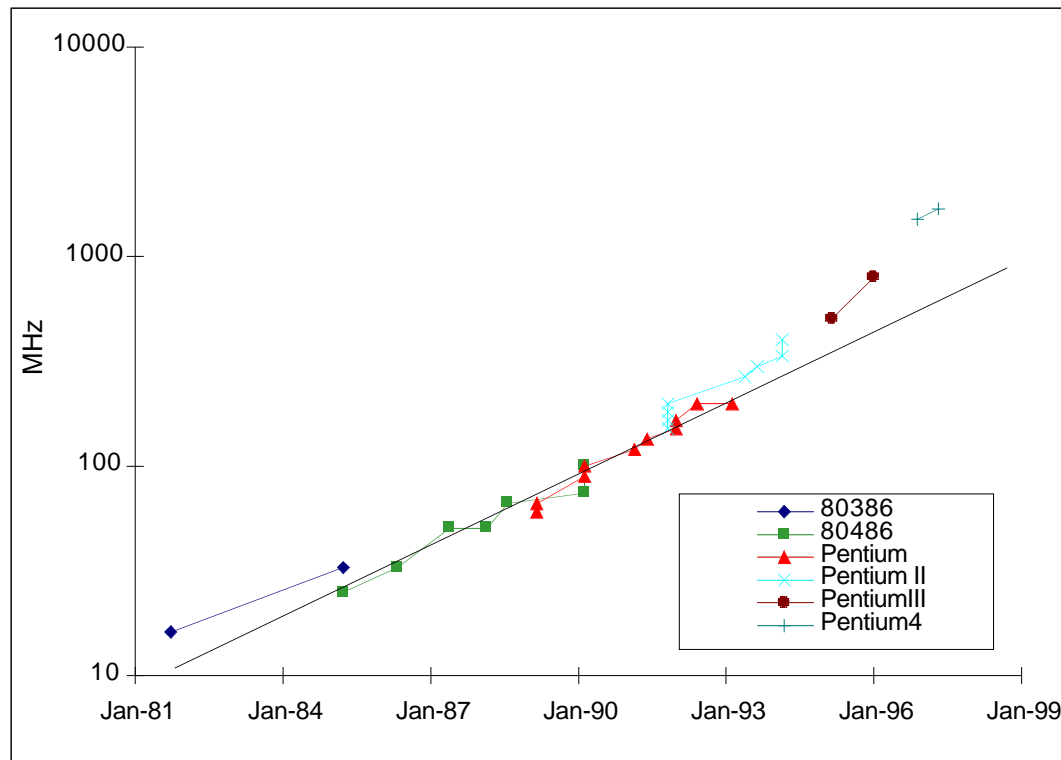
- Plot of IPC
 - Compiler + IPC
 - 1.5x / generation
 - Until PIII, now falling
- There is a lot of hardware to make this happen
 - It costs in power



SpecInt/MHz

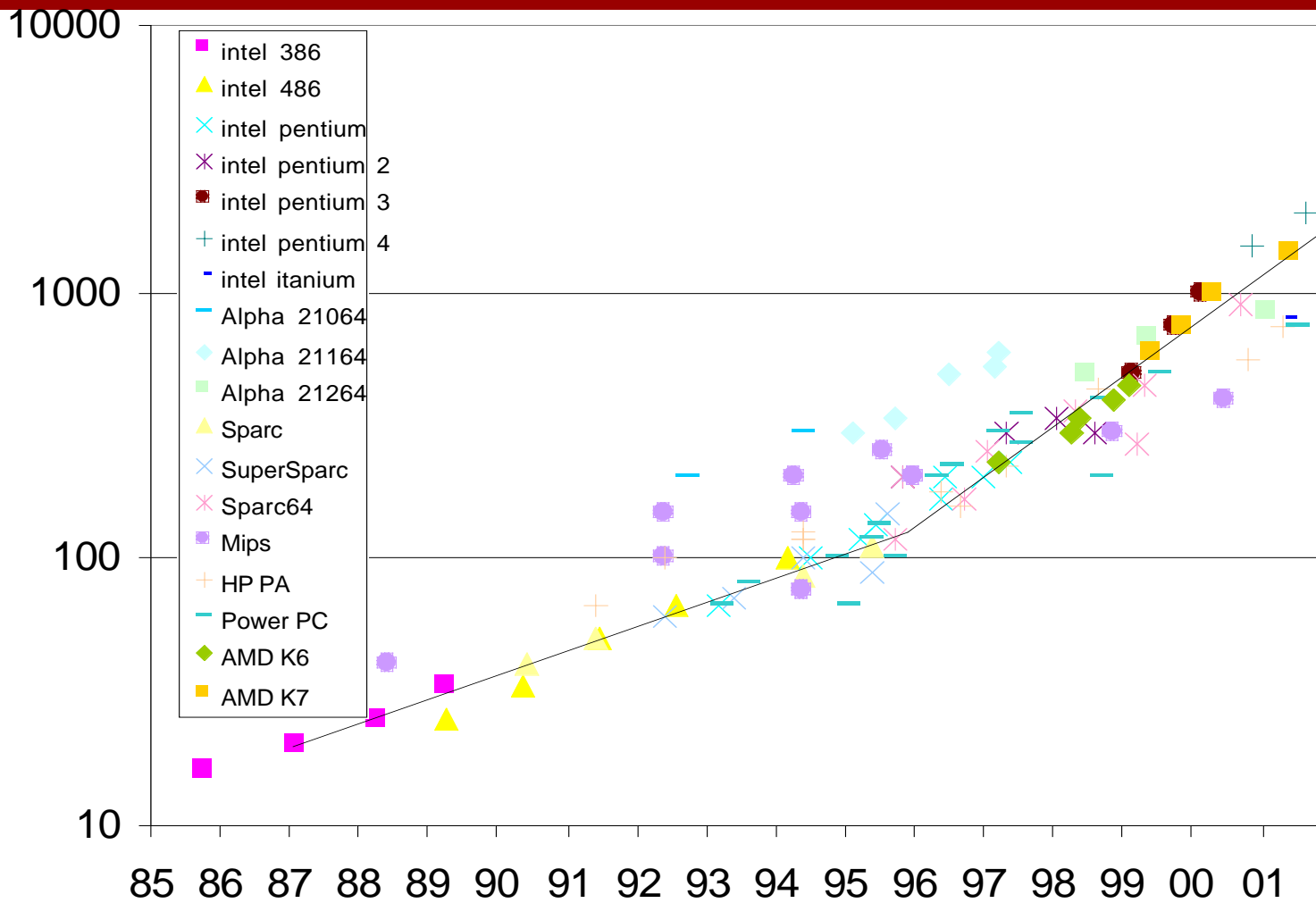


Clock Frequency



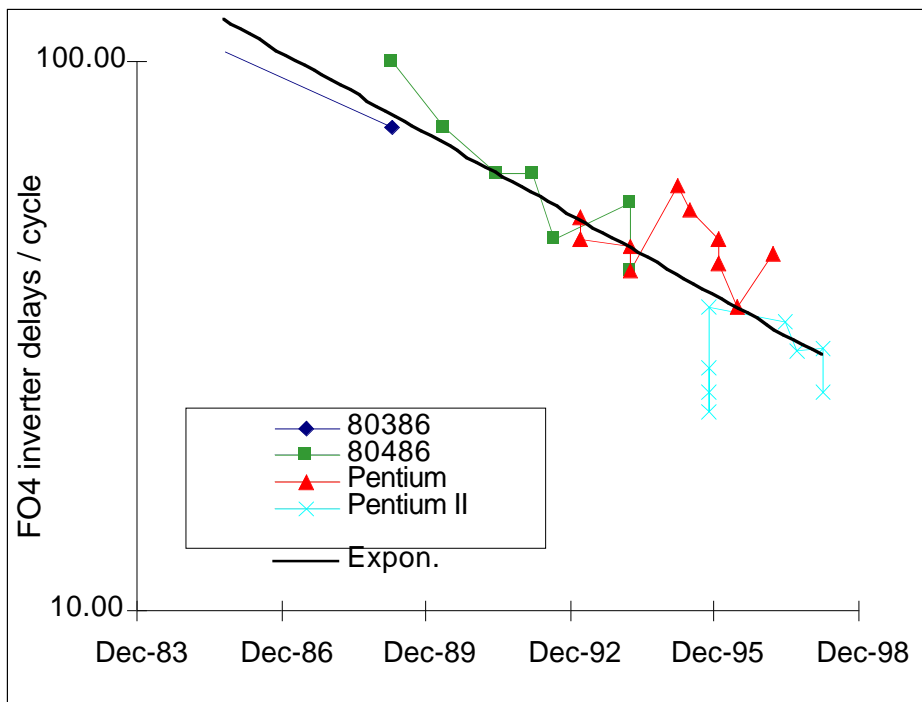
- Most of performance comes from clock scaling
 - Clock frequency double each generation
- Two factors contribute: technology (1.4x/gen), circuit design

Clock Frequency Scaling



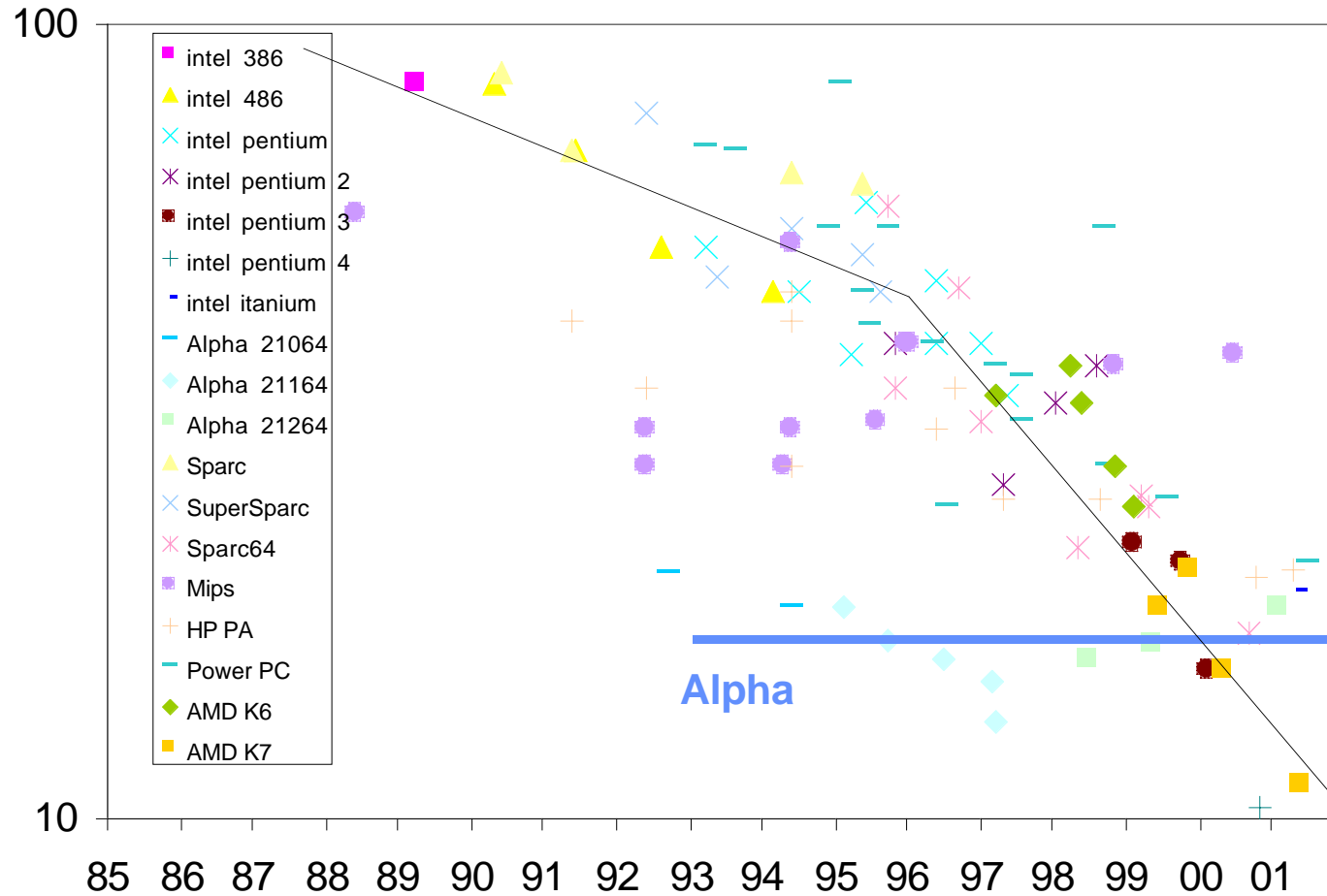
Clock Cycle in 'FO4'

- Clock speed has been scaling faster than base technology
- Number of FO4 delays in a cycle has been falling



- Number of gates decrease 1.4x each generation
- Caused by:
 - Faster circuit families (dynamic logic)
 - Better optimization
 - Better micro-architecture
 - Better adder/mem arch
- Implies increased power

Clock Cycle in 'FO4'



Wire Layers

Not all wiring layers have the same characteristics

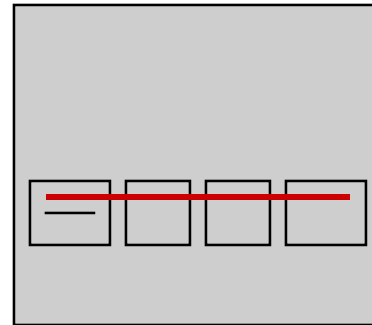
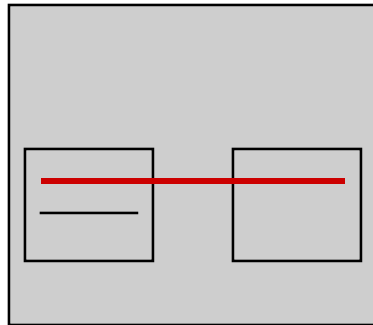
- Today have three types of levels
 - M1, sometimes M2
 - Finest pitch, highest resistance, local interconnection in a cell
 - M2-4?
 - Normal routing level, most of the wires
 - M5+
 - Thick coarse metal, used for global wires
 - When scaling forces thinner metal, create new top layer

Noise Issues

- Two main noise sources for wires
 - Capacitance coupling
 - Inductive coupling
- Capacitance coupling is mostly a nearest neighbor issue
 - High aspect ratio wires make this worse
 - Real push for low- κ dielectric between wires
- Inductive coupling
 - Is much more complex to analyze
 - Depends on where the return currents flow
 - Reduce these problem by design constraints
 - Gnd returns in buses, power and gnd planes (e.g. 21264)

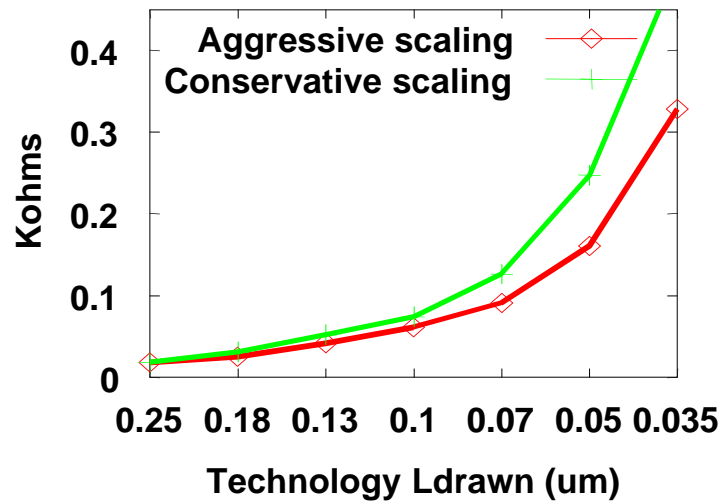
This is, and will continue to be, managed by design rules

Scaling Global Wires

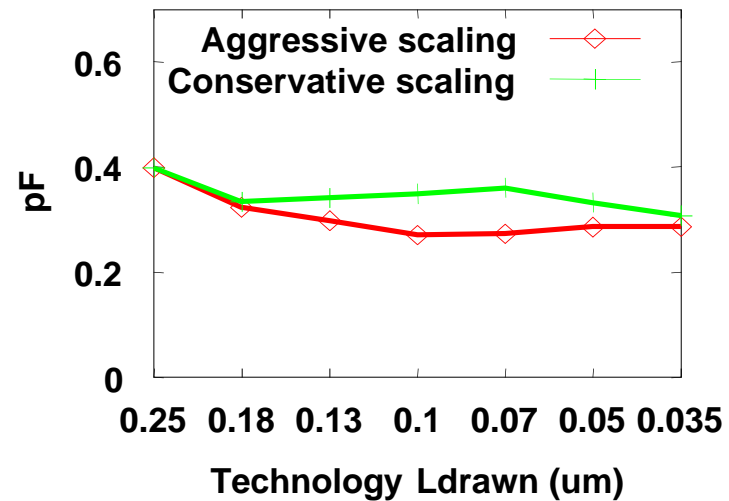


- R gets quite a bit worse with scaling; C basically constant

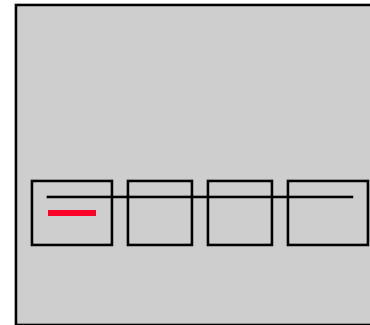
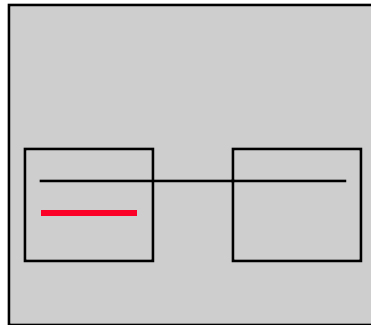
Semi-global wire resistance, 1mm long



Semi-global wire capacitance, 1mm long

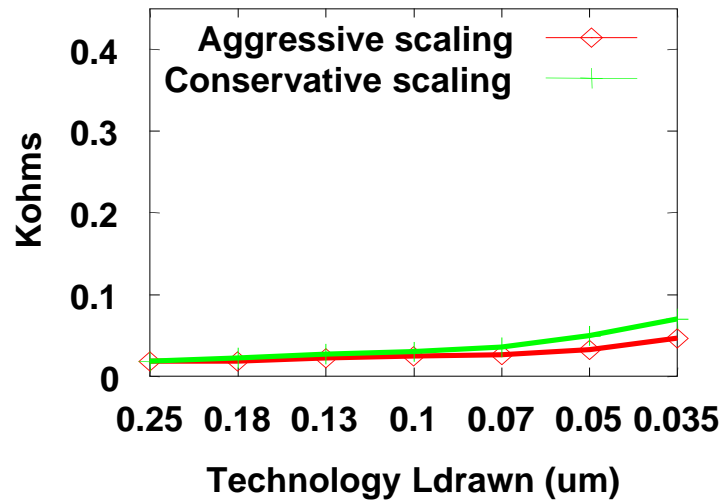


Scaling Module Wires

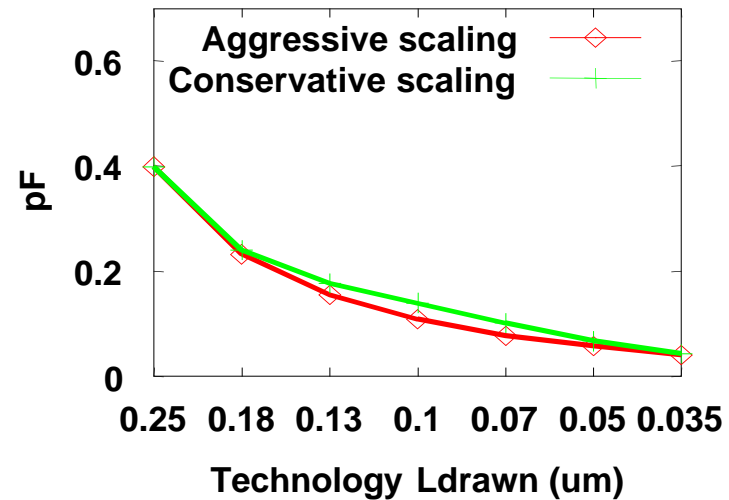


- R is basically constant, and C falls linearly with scaling

Semi-global wire resistance, scaled length

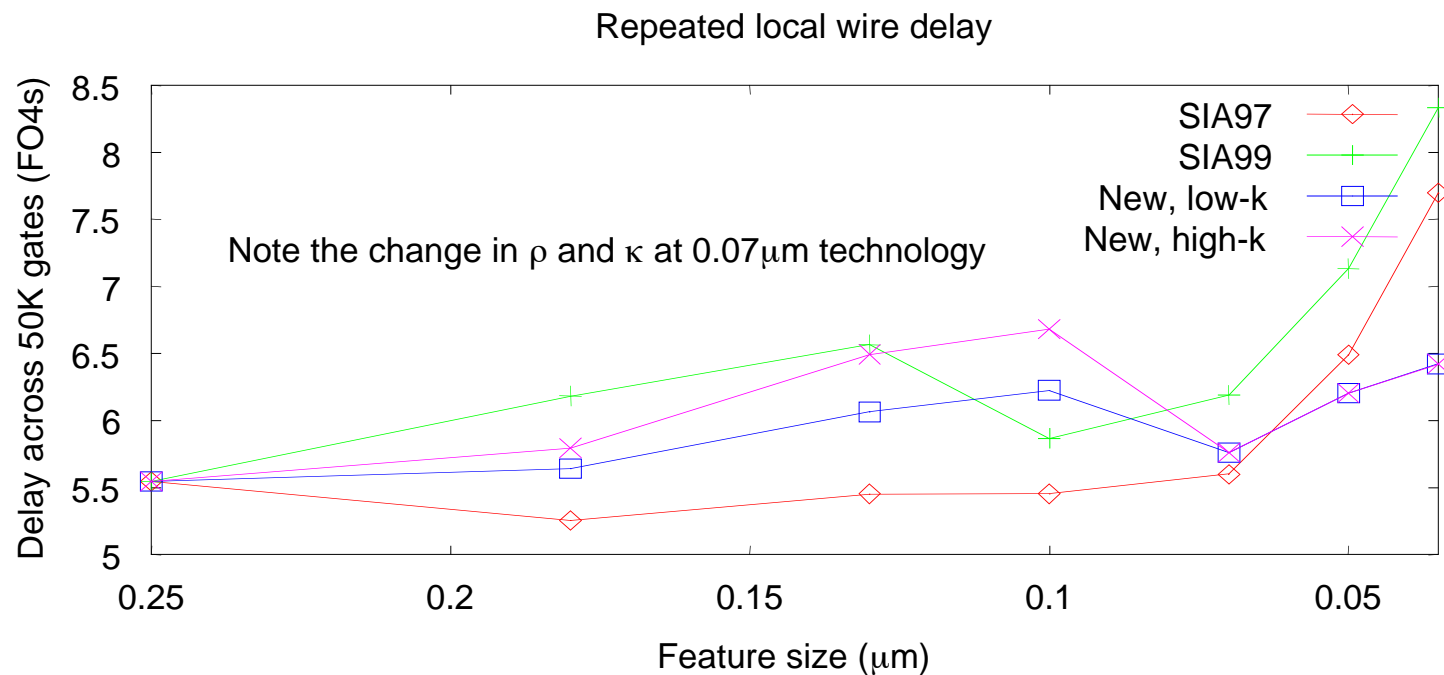


Semi-global wire capacitance, scaled length



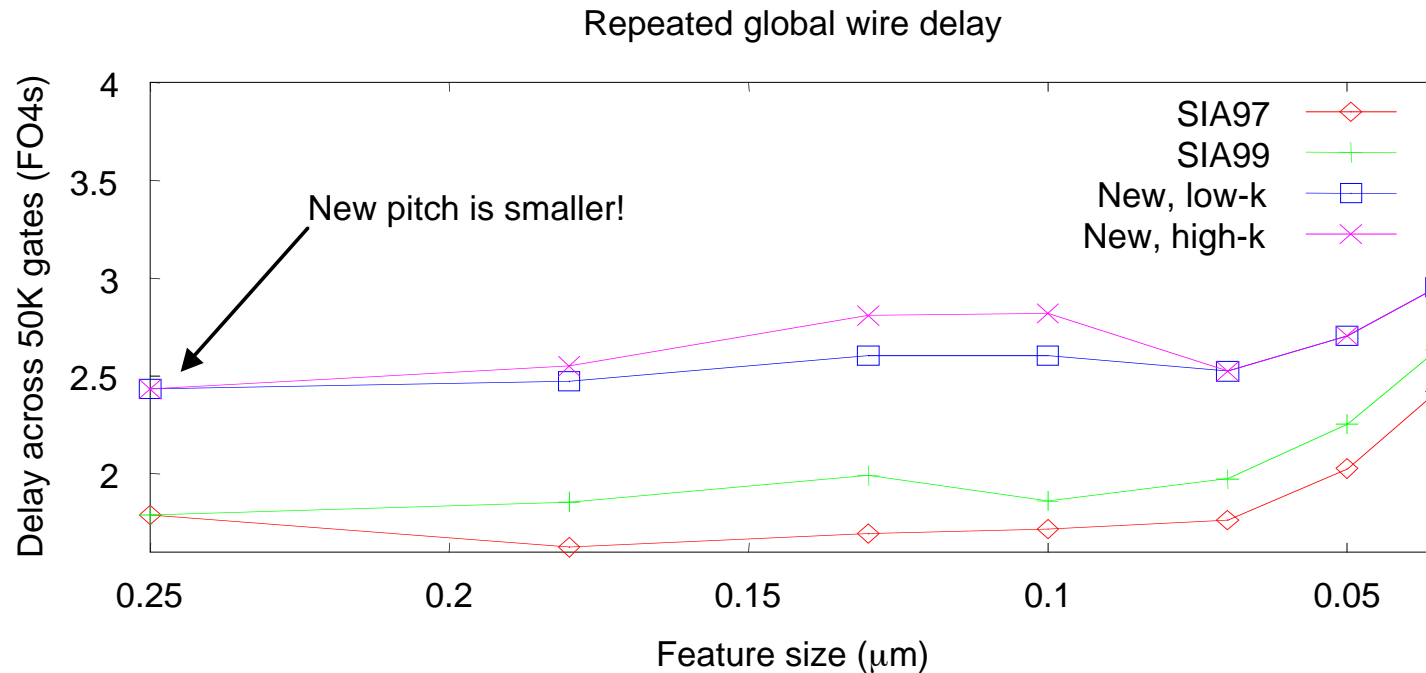
Scaling Local Wires

- Normalize a local wire to an inverter loaded with fanout=4
 - This wire spans the edge of a block of 50K gates
- Bandwidth across a 50K gate block scales with technology
 - $1.6/L_{\text{drawn}}$ Tb/s (6.4 Tb/s in $0.25\mu\text{m}$; ~ 30 Tb/s in $0.05\mu\text{m}$)



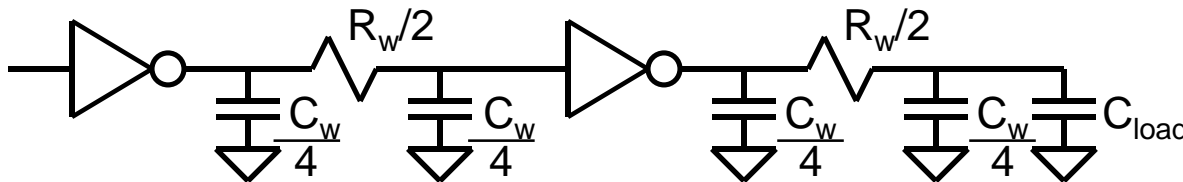
Local Wires on Top Metal

- Also look at global wires that span edge of 50K gate blocks
 - Nobody would really route in local metal, anyway



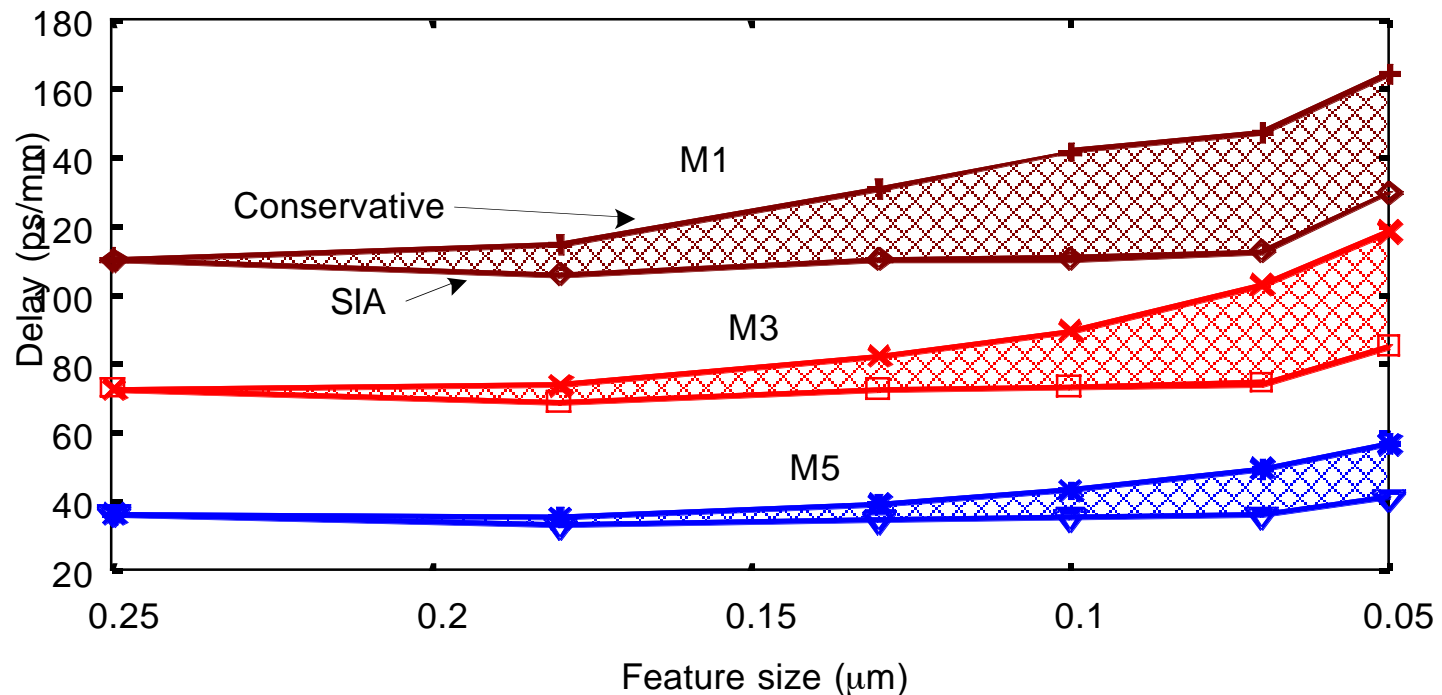
Wires Become Active

- Since the wire delay increases with length
 - Use regeneration to speed up long wires
- Velocity of wire become geometric mean = $k (FO4 R_w C_w)^{1/2}$
 - Compensate for decreasing wire performance
 - Repeater density increases w/ technology
 - But roughly constant in grids
- Note that wires are now active
 - Can think of doing some interesting stuff in the wires
 - More on that later



Signal Velocity for Repeated wires

- Under SIA scaling, pretty constant over many generations
- Under conservative scaling, slow change at sub-0.1 μm techs
 - Makes wire delay increase slowly



Caveat:

- There is some concern that these wire models are optimistic
 - Overhead of barrier layers
 - Scattering changes when the wire width $<$ mean free path
- Potential for conductivity of Cu to fall at small dimensions
 - Surface design will be critical for low resistance wires

